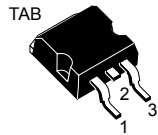
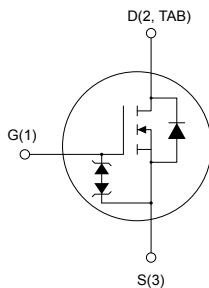


N-channel 900 V, 600 mΩ typ., 8 A MDmesh K5 Power MOSFET in a D²PAK package


D²PAK


AM01476v1_tab


Product status link
[STB8N90K5](#)
Product summary

| | |
|-------------------|--------------------|
| Order code | STB8N90K5 |
| Marking | 8N90K5 |
| Package | D ² PAK |
| Packing | Tape and reel |

Features

| Order code | V _{DS} | R _{DS(on)} max. | I _D |
|------------|-----------------|--------------------------|----------------|
| STB8N90K5 | 900 V | 680 Ω | 8 A |

- Ultra-low gate charge
- Very low FoM (figure of merit)
- Zener-protected
- 100% avalanche tested

Applications

- Switching applications

Description

This very high voltage N-channel Power MOSFET is designed using MDmesh K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

1 Electrical ratings

Table 1. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|---|------------|------------------|
| V_{GS} | Gate-source voltage | ± 30 | V |
| I_D | Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$ | 8 | A |
| | Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$ | 5 | |
| $I_{DM}^{(1)}$ | Drain current (pulsed) | 32 | A |
| P_{TOT} | Total power dissipation at $T_C = 25\text{ }^\circ\text{C}$ | 130 | W |
| $dv/dt^{(2)}$ | Peak diode recovery voltage slope | 4.5 | V/ns |
| $dv/dt^{(3)}$ | MOSFET dv/dt ruggedness | 50 | V/ns |
| T_{stg} | Storage temperature range | -55 to 150 | $^\circ\text{C}$ |
| T_J | Operating junction temperature range | | $^\circ\text{C}$ |

1. Pulse width is limited by safe operating area.
2. $I_{SD} \leq 8\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DS} (\text{peak}) < V_{(BR)DSS}$.
3. $V_{DD} \leq 720\text{ V}$.

Table 2. Thermal data

| Symbol | Parameter | Value | Unit |
|------------------|---|-------|---------------------------|
| R_{thJC} | Thermal resistance, junction-to-case | 0.96 | $^\circ\text{C}/\text{W}$ |
| $R_{thJA}^{(1)}$ | Thermal resistance, junction-to-ambient | 30 | $^\circ\text{C}/\text{W}$ |

1. When mounted on a standard 1 inch² area of FR-4 PCB with 2-oz copper.

Table 3. Avalanche characteristics

| Symbol | Parameter | Value | Unit |
|----------|--|-------|------|
| I_{AR} | Avalanche current, repetitive or non-repetitive (pulse width limited by T_J max.) | 2.7 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_J = 25\text{ }^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$) | 250 | mJ |

2 Electrical characteristics

$T_C = 25\text{ °C}$ unless otherwise specified.

Table 4. Static

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|-----------------------------------|---|------|------|----------|---------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage | $V_{GS} = 0\text{ V}$, $I_D = 1\text{ mA}$ | 900 | - | - | V |
| I_{DSS} | Zero gate voltage drain current | $V_{GS} = 0\text{ V}$, $V_{DS} = 900\text{ V}$ | - | - | 1 | μA |
| | | $V_{GS} = 0\text{ V}$, $V_{DS} = 900\text{ V}$, $T_C = 125\text{ °C}^{(1)}$ | - | - | 50 | |
| I_{GSS} | Gate-body leakage current | $V_{DS} = 0\text{ V}$, $V_{GS} = \pm 20\text{ V}$ | - | - | ± 10 | μA |
| $V_{GS(th)}$ | Gate threshold voltage | $V_{DS} = V_{GS}$, $I_D = 100\text{ }\mu\text{A}$ | 3 | 4 | 5 | V |
| $R_{DS(on)}$ | Static drain-source on-resistance | $V_{GS} = 10\text{ V}$, $I_D = 4\text{ A}$ | - | 600 | 680 | m Ω |

1. Specified by design, not tested in production.

Table 5. Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-------------------|--|---|------|------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 100\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0\text{ V}$ | - | 426 | - | pF |
| C_{oss} | Output capacitance | | - | 41 | - | pF |
| C_{rss} | Reverse transfer capacitance | | - | 1.2 | - | pF |
| $C_{o(tr)}^{(1)}$ | Equivalent output capacitance time related | $V_{DS} = 0\text{ to }720\text{ V}$, $V_{GS} = 0\text{ V}$ | - | 75 | - | pF |
| $C_{o(er)}^{(2)}$ | Equivalent output capacitance energy related | | - | 28 | - | pF |
| R_g | Intrinsic gate resistance | $f = 1\text{ MHz}$, $I_D = 0\text{ A}$ | - | 7 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 720\text{ V}$, $I_D = 8\text{ A}$, $V_{GS} = 0\text{ to }10\text{ V}$ (see the Figure 14. Test circuit for gate charge behavior) | - | 11 | - | nC |
| Q_{gs} | Gate-source charge | | - | 3.5 | - | nC |
| Q_{gd} | Gate-drain charge | | - | 4.8 | - | nC |

1. $C_{o(tr)}$ is a constant capacitance value that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

2. $C_{o(er)}$ is a constant capacitance value that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

Table 6. Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|--------------|---------------------|---|------|------|------|------|
| $t_{d(on)}$ | Turn-on delay time | $V_{DD} = 450\text{ V}$, $I_D = 4\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = 10\text{ V}$ | - | 14.7 | - | ns |
| t_r | Rise time | | - | 13.2 | - | ns |
| $t_{d(off)}$ | Turn-off delay time | (see the Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform) | - | 36.4 | - | ns |
| t_f | Fall time | | - | 13.5 | - | ns |

Table 7. Source-drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|---|------|------|------|---------------|
| I_{SD} | Source-drain current | | - | - | 8 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | - | - | 32 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $V_{GS} = 0\text{ V}$, $I_{SD} = 8\text{ A}$ | - | - | 1.5 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 4\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, | - | 371 | - | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 60\text{ V}$ | - | 4.27 | - | μC |
| I_{RRM} | Reverse recovery current | (see the Figure 15. Test circuit for inductive load switching and diode recovery times) | - | 23 | - | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 8\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, | - | 582 | - | ns |
| Q_{rr} | Reverse recovery charge | $V_{DD} = 60\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$ | - | 5.73 | - | μC |
| I_{RRM} | Reverse recovery current | (see the Figure 15. Test circuit for inductive load switching and diode recovery times) | - | 19.7 | - | A |

1. Pulse width is limited by safe operating area.
2. Pulse test: pulse duration = 300 μs , duty cycle 1.5%.

2.1 Electrical characteristics (curves)

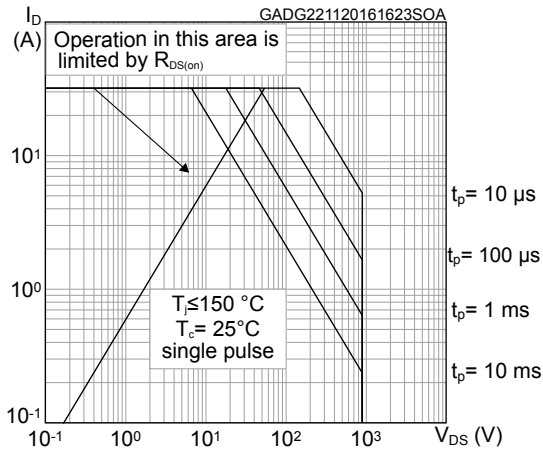
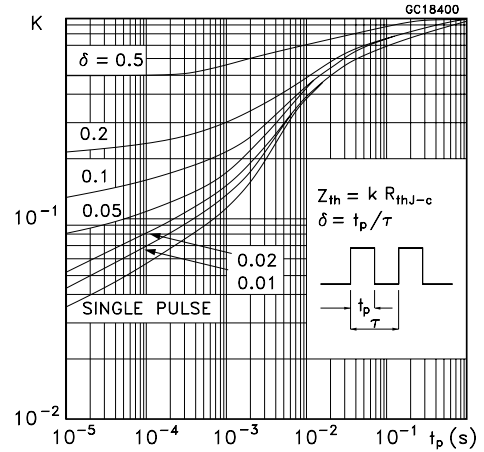
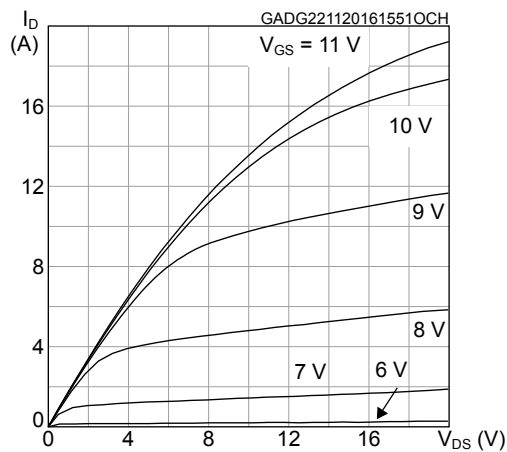
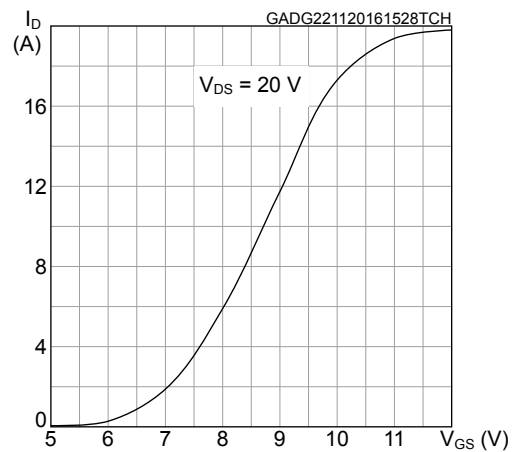
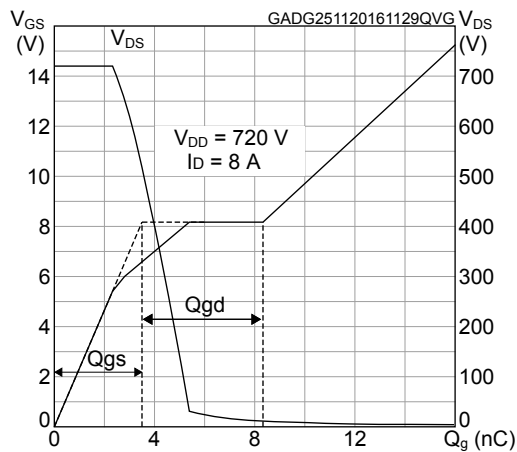
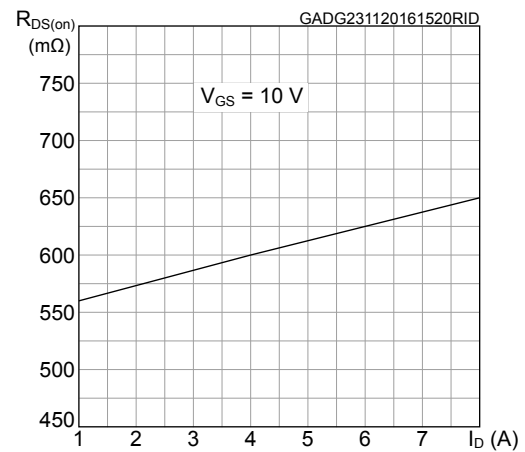
Figure 1. Safe operating area

Figure 2. Normalized transient thermal impedance

Figure 3. Typical output characteristics

Figure 4. Typical transfer characteristics

Figure 5. Typical gate charge characteristics

Figure 6. Typical drain-source on-resistance


Figure 7. Typical capacitance characteristics

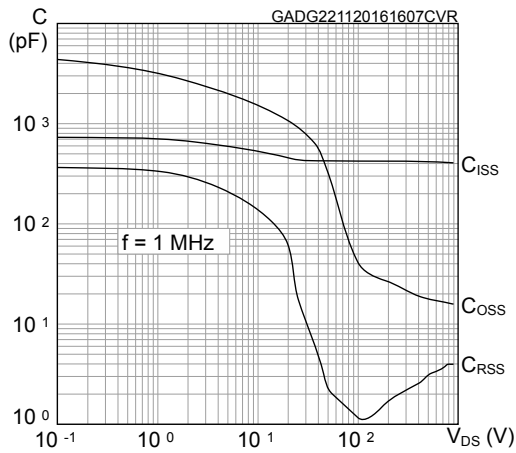


Figure 8. Normalized gate threshold vs temperature

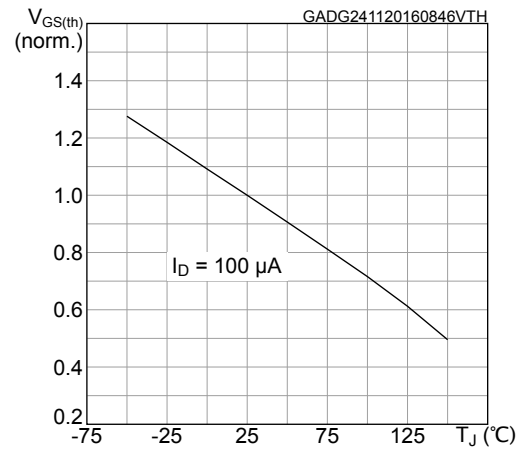


Figure 9. Normalized on-resistance vs temperature

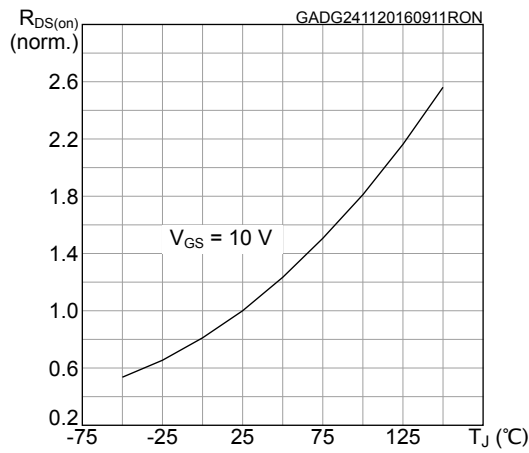


Figure 10. Normalized breakdown voltage vs temperature

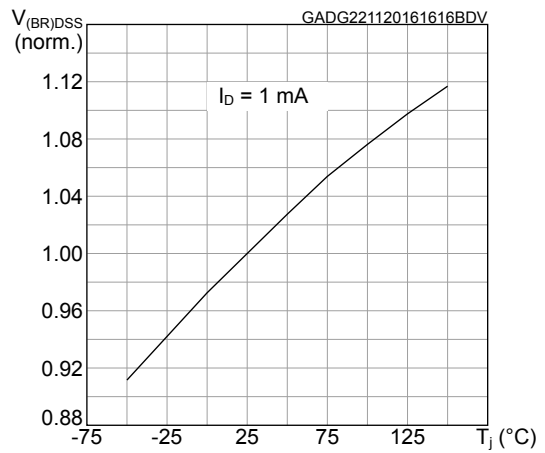


Figure 11. Maximum avalanche energy vs temperature

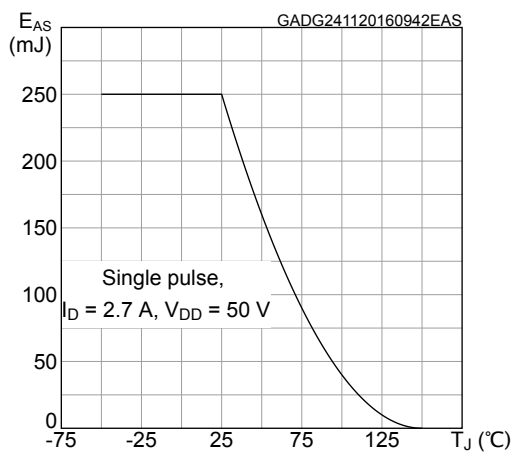
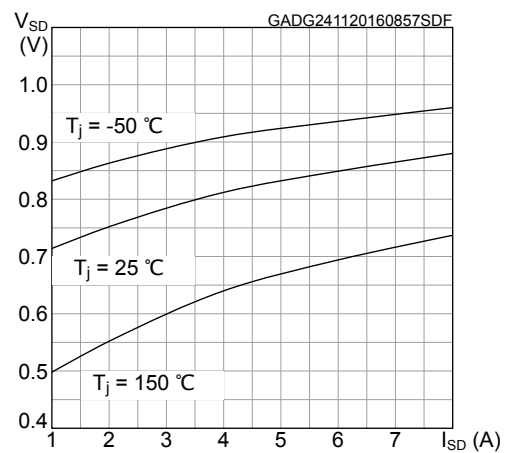
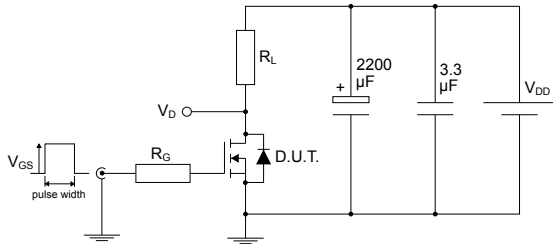


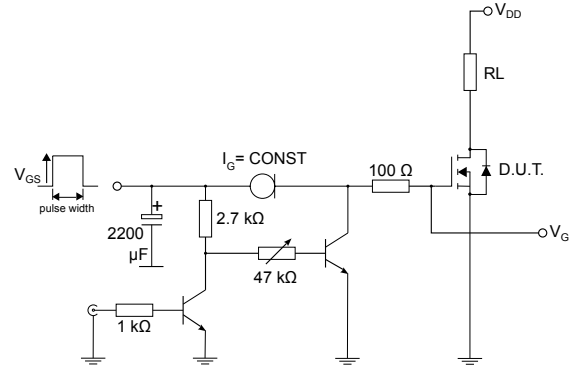
Figure 12. Typical reverse diode forward characteristics



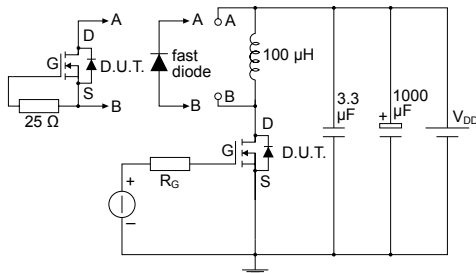
3 Test circuits

Figure 13. Test circuit for resistive load switching times


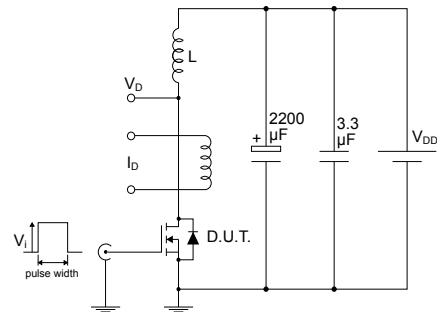
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Figure 14. Test circuit for gate charge behavior


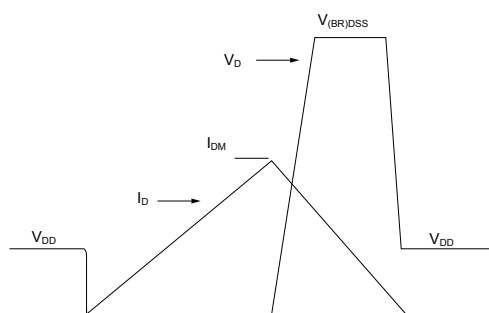
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Figure 15. Test circuit for inductive load switching and diode recovery times


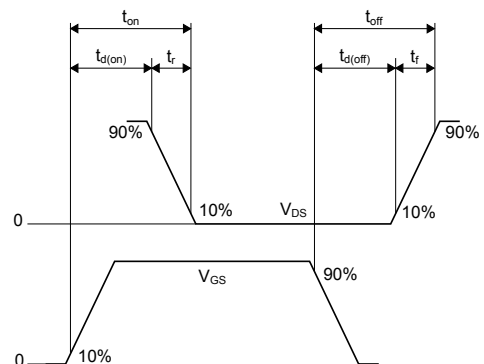
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Figure 16. Unclamped inductive load test circuit


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Figure 17. Unclamped inductive waveform


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Figure 18. Switching time waveform


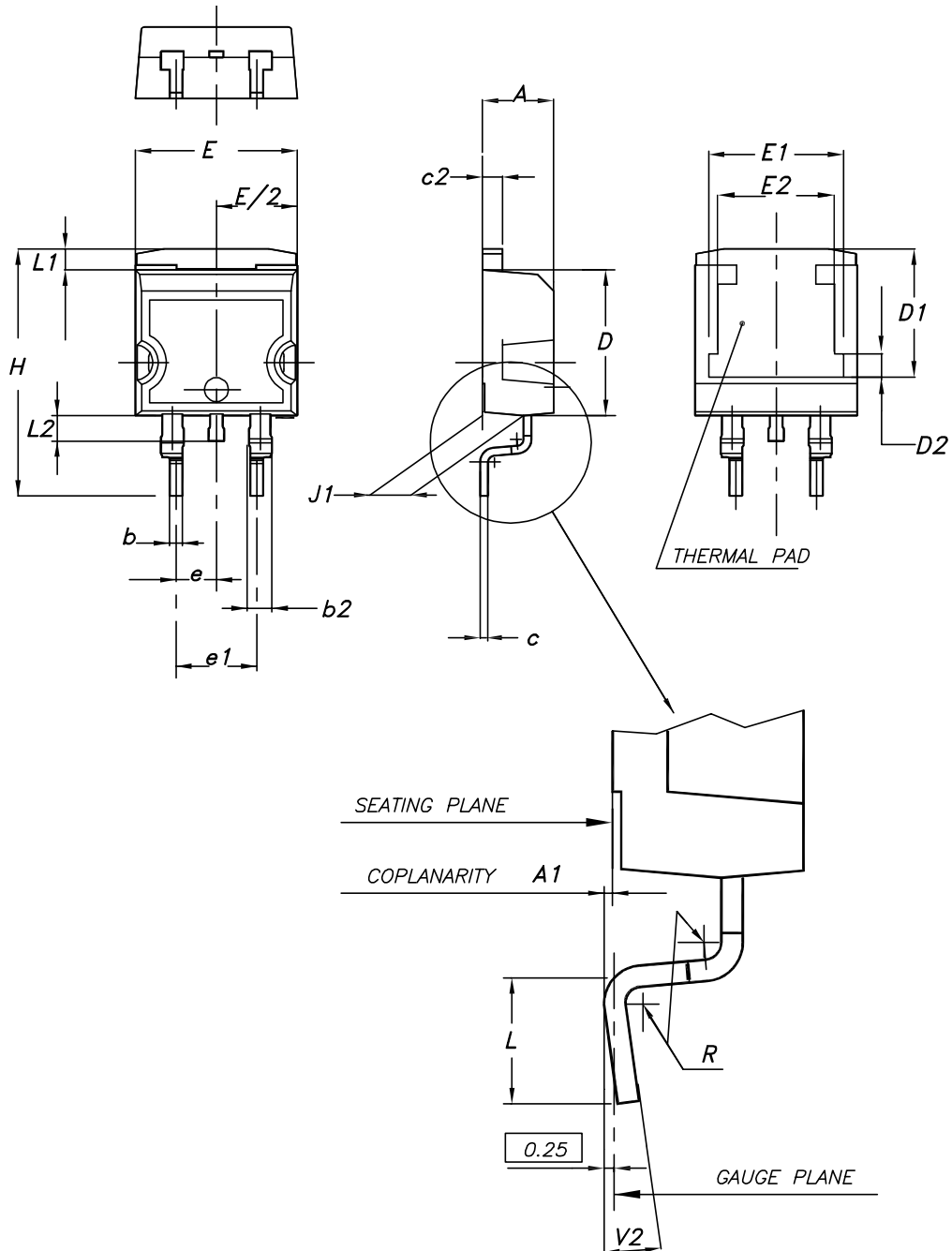
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4 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 D²PAK (TO-263) type A package information

Figure 19. D²PAK (TO-263) type A package outline

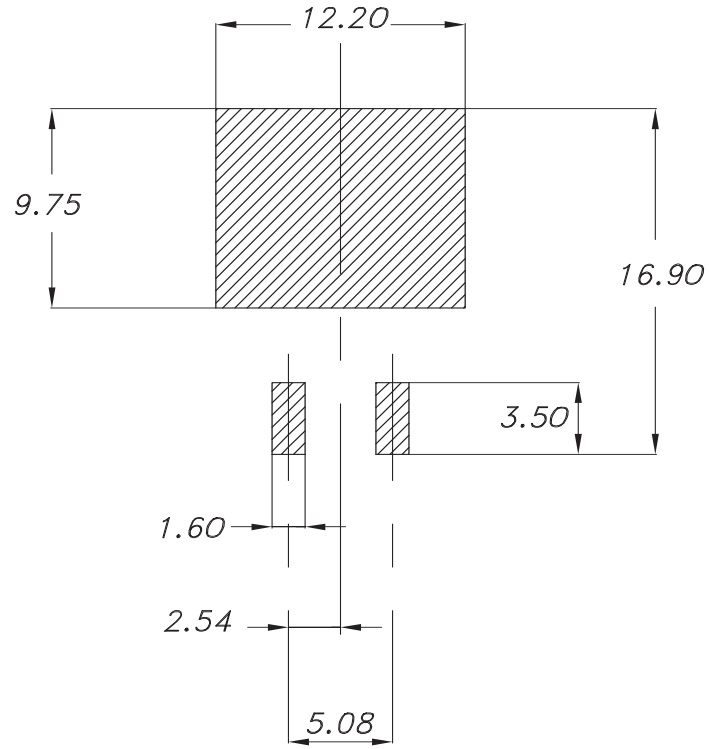


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Table 8. D²PAK (TO-263) type A package mechanical data

| Dim. | mm | | |
|------|-------|------|-------|
| | Min. | Typ. | Max. |
| A | 4.40 | | 4.60 |
| A1 | 0.03 | | 0.23 |
| b | 0.70 | | 0.93 |
| b2 | 1.14 | | 1.70 |
| c | 0.45 | | 0.60 |
| c2 | 1.23 | | 1.36 |
| D | 8.95 | | 9.35 |
| D1 | 7.50 | 7.75 | 8.00 |
| D2 | 1.10 | 1.30 | 1.50 |
| E | 10.00 | | 10.40 |
| E1 | 8.30 | 8.50 | 8.70 |
| E2 | 6.85 | 7.05 | 7.25 |
| e | | 2.54 | |
| e1 | 4.88 | | 5.28 |
| H | 15.00 | | 15.85 |
| J1 | 2.49 | | 2.69 |
| L | 2.29 | | 2.79 |
| L1 | 1.27 | | 1.40 |
| L2 | 1.30 | | 1.75 |
| R | | 0.40 | |
| V2 | 0° | | 8° |

Figure 20. D²PAK (TO-263) recommended footprint (dimensions are in mm)



0079457_Rev27_footprint

Revision history

Table 9. Document revision history

| Date | Version | Changes |
|-------------|---------|---|
| 28-Nov-2016 | 1 | First release. |
| 06-Nov-2025 | 2 | Updated Section 4: Package information . Minor text changes. |

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